

AO4437
P-Channel Enhancement Mode Field Effect Transistor


General Description

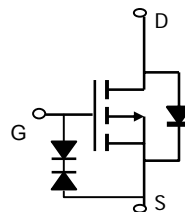
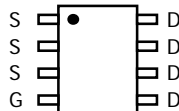
The AO4437 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications. It is ESD protected.

Standard Product AO4437 is Pb-free (meets ROHS & Sony 259 specifications). AO4437L is a Green Product ordering option. AO4437 and AO4437L are electrically identical.

Features

V_{DS} (V) = -12V
 I_D = -11 A (V_{GS} = -4.5V)
 $R_{DS(ON)} < 16m\Omega$ (V_{GS} = -4.5V)
 $R_{DS(ON)} < 20m\Omega$ (V_{GS} = -2.5V)
 $R_{DS(ON)} < 25m\Omega$ (V_{GS} = -1.8V)
 ESD Rating: 4KV HBM

SOIC-8
Top View



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	-12	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current ^A	I_D	-11	A
$T_A=25^\circ\text{C}$			
$T_A=70^\circ\text{C}$		-9	
Pulsed Drain Current ^B	I_{DM}	-20	
Power Dissipation ^A	P_D	3	W
$T_A=25^\circ\text{C}$			
$T_A=70^\circ\text{C}$		2.1	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ\text{C}$

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	31	40	$^\circ\text{C/W}$
$t \leq 10\text{s}$				
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	63	75	$^\circ\text{C/W}$
Steady-State				
Maximum Junction-to-Lead ^C	$R_{\theta JL}$	21	30	$^\circ\text{C/W}$
Steady-State				

Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}$, $V_{GS}=0\text{V}$	-12			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-9.6\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^{\circ}\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}$, $V_{GS}=\pm 4.5\text{V}$			± 1	μA
		$V_{DS}=0\text{V}$, $V_{GS}=\pm 8\text{V}$			± 10	μA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_D=-250\mu\text{A}$	-0.3	-0.55	-1	
$I_{D(ON)}$	On state drain current	$V_{GS}=-4.5\text{V}$, $V_{DS}=-5\text{V}$	-20			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}$, $I_D=-11\text{A}$ $T_J=125^{\circ}\text{C}$		12.4 17	16 21	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}$, $I_D=-10\text{A}$		15.9	20	$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}$, $I_D=-6\text{A}$		20.4	25	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}$, $I_D=-11\text{A}$		38		S
V_{SD}	Diode Forward Voltage	$I_S=-1\text{A}$, $V_{GS}=0\text{V}$		-0.74	-1	V
I_S	Maximum Body-Diode Continuous Current				-4.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=-6\text{V}$, $f=1\text{MHz}$		3960	4750	pF
C_{oss}	Output Capacitance			910		pF
C_{rss}	Reverse Transfer Capacitance			757		pF
R_g	Gate resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$		6.9	8.5	Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	$V_{GS}=-4.5\text{V}$, $V_{DS}=-6\text{V}$, $I_D=-11\text{A}$		37	47	nC
Q_{gs}	Gate Source Charge			4.5		nC
Q_{gd}	Gate Drain Charge			11		nC
$t_{D(on)}$	Turn-On Delay Time	$V_{GS}=-4.5\text{V}$, $V_{DS}=-6\text{V}$, $R_L=0.55\Omega$, $R_{GEN}=3\Omega$		15		ns
t_r	Turn-On Rise Time			43		ns
$t_{D(off)}$	Turn-Off Delay Time			158		ns
t_f	Turn-Off Fall Time			95		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-11\text{A}$, $di/dt=100\text{A}/\mu\text{s}$		64		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-11\text{A}$, $di/dt=100\text{A}/\mu\text{s}$		50		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $\leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

D: The static characteristics in Figures 1 to 6, 12, 14 are obtained using 80 μs pulses, duty cycle 0.5% max.

E: These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The SOA curve provides a single pulse rating.

Rev2: August 2005

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

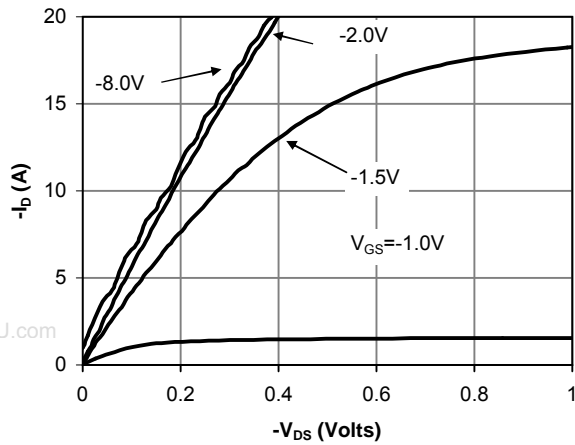


Fig 1: On-Region Characteristics

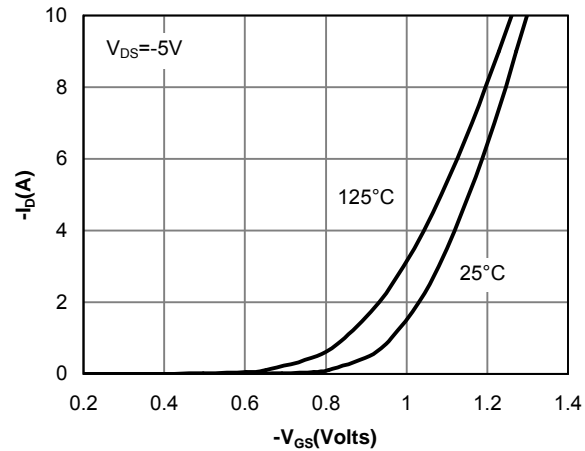


Figure 2: Transfer Characteristics

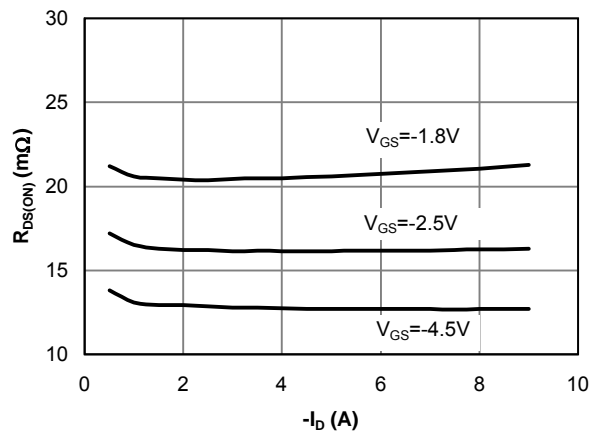


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

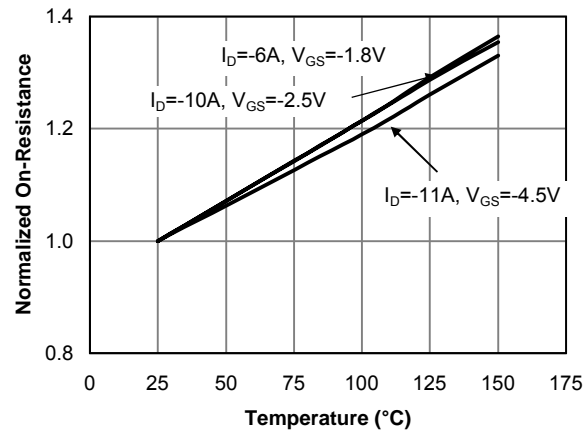


Figure 4: On-Resistance vs. Junction Temperature

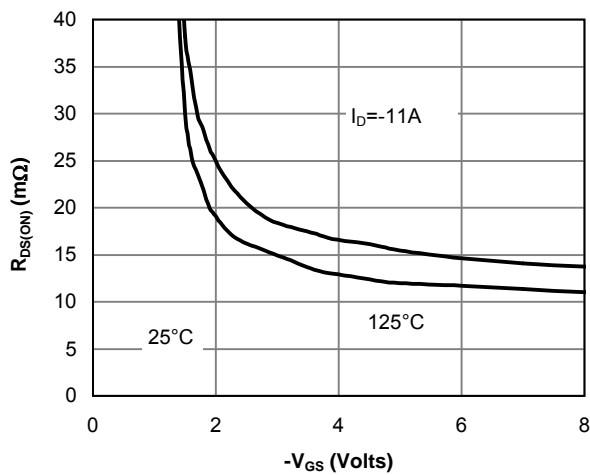


Figure 5: On-Resistance vs. Gate-Source Voltage

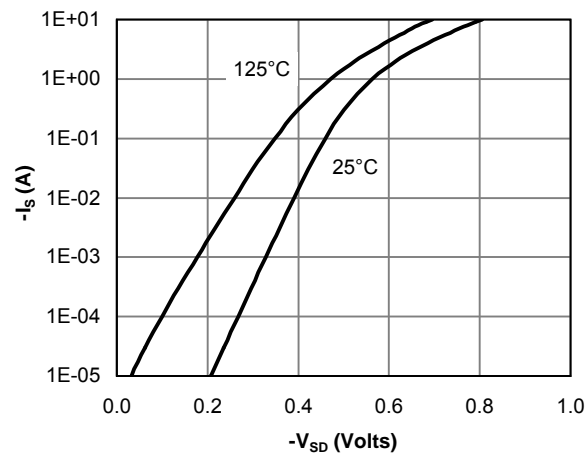


Figure 6: Body-Diode Characteristics